Applicant(s)/Patent Under Application/Control No. Reexamination 10/667,001 BATES ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2191 Anil Khatri

U.S. PATENT DOCUMENTS

*		Document Number	Date MM-YYYY	Name	Classification
*		Country Code-Number-Kind Code	08-1999	Meier et al.	717/129
*	A	US-5,933,639	09-2006	Alpern, David M.	717/124
*	В	US-7,107,578 US-6,263,489	07-2001	Olsen et al.	717/129
*	C	US-5,764,989	06-1998	Gustafsson et al.	717/129
*	D	US-6,895,577	05-2005	Noble et al.	717/126
*	E	US-6,721,941	04-2004	Morshed et al.	. 717/127
*	F	US-6.817,010	11-2004	Aizenbud-Reshef et al.	717/127
*	G	US-7,133,820	11-2006	Pennello et al.	703/22
*	Н	US-6,681,384	01-2004	Bates et al.	717/129
-	<u> </u>	US-			
 	K	US-			
-	 ``	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*	$\overline{}$	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P_			·		
	a					
	R					
	s					
	т		<u> </u>	NON PATENT DOCUM		

NON-PATENT DOCUMENTS

NON-PATENT DOCUMENTS					
	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
U	Chem et al, "Debugging with control flow breakpoints", ACM AOSD, pp 96-106, 2007				
٧	Koch et al, "Breakpoints and breakpoint detection in source level emulation", IEEE ISSS, pp 26-31, 1996				
w	Iqbal et al, "Undersanding and developing models for detecting and differentiating breakpoints during interactive tasks" ACM CHI, pp 697-706, 2007				
х	Wahbe et al, "Practical data breakpoints: design and implementations", ACM SIGPLAN PLDI, pp 1-12, 1993				
	v w				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademer< Office PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 20070519